

<b>Notice of References Cited</b>	Application/Control No. 10/625,878		Applicant(s)/Patent Under Reexamination KEENER, MARK BRADFORD	
	Examiner Tan Dean D. Nguyen		Art Unit 3689	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,864,865	01-1999	Lakis, David Michael	707/103R
*	B	US-6,670,973	12-2003	Hill et al.	715/853
*	C	US-2003/0085931	05-2003	Card et al.	345/853
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	408329156A		JAPAN		
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.